COMPARATIVE PERFORMANCE ANALYSIS OF LOW POWER FULL ADDER DESIGN IN DIFFERENT LOGICS IN 22nm SCALING TECHNOLOGY

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ABSTRACT

This paper gives the comparison of performance of full adder design in terms of area, power and delay in different logic styles. Full adder design achieves low power using the Transmission Gate logic compared to all other topologies such as Basic CMOS, Pass Transistor and GDI techniques but it make use of more number of transistors compared to GDI. GDI occupies less area compared to all other logic design styles. This paper presents the simulated outcome using Tanner tools and also H-Spice tool which shows power and speed comparison of different full adder designs. All simulations have been performed in 90nm, 45nm and 22nm scaling parameters using Predictive Technology Models in H-Spice tool.

KEYWORDS

CMOS, SGMOSFET, DGMOSFET, Transmission Gate, GDI, Predictive Technology.

1. INTRODUCTION

To reduce the size of chip, the complexity in the circuits has increased drastically, because of that the power dissipation and performance of the circuit are being affected. So, there is concern towards circuits design in low power VLSI design to reduce the chip area and power dissipation [1]. There are two types of power dissipations in MOSFET, namely static power dissipation and dynamic power dissipation. In Static power dissipation, there are few parameters which show effect on operation of device, among them mainly sub-threshold leakage, gate direct tunneling leakage, reverse-biased junction leakage and gate induced drain leakage shows the major effect in various scaling parameters. In Dynamic power dissipation switching and short circuit power will have the effect. The static and dynamic power dissipations are calculated theoretically from the equations shown in 1 and 2 respectively.
International Journal on Cybernetics & Informatics (IJCI) Vol. 5, No. 4, August 2016

\[ P_s = I_{cc} \cdot V_{DD} \] .................. (1)

\[ P_D = \frac{1}{2} C_L (\Delta V_0)^2 f \] .................. (2)

Where, \( I_{cc} \) = Sum of leakage current

\( V_{DD} \) = Supply voltage

\( C_L \) = Load capacitance

\( \Delta V_0 \) = Logic voltage swing

\( f \) = Frequency of switching

Power delay product (PDP=P_{AVG}*T) is a parameter we used for comparison between various circuits to estimate the optimised results which can be operated at different frequency regions. A full adder is the base in digital circuits employed for performing arithmetical and logical operations, compressors, comparators and parity checkers. In present world of VLSI system applications such as specific DSP architecture, Systolic array design, microprocessors, FIR Filters, perform fundamental operations. Full adder is a core element that determines the overall performance of arithmetic circuit. In this paper, we designed improved full adder which operates in 22nm scaling technology using transmission gate (TG) logic.

This paper summarizes as follows, Section 2 Power Consumption in VLSI Circuits, Section 3 describes the topologies of the implemented low power full adders. Section 4 represents the proposed circuit designs. The simulation results are shown and discussed from the observations in waveforms and power delay product values of different circuits presented in section 5 the conclusions in section 6 followed references in Section 7.

**2. POWER CONSUMPTION IN VLSI CIRCUITS**

**2.1 Need for Low Power design:**

Especially for portable devices the Battery lifetime plays very important role. Any customer while purchasing any portable device will definitely enquire about its battery life and reacts accordingly. A portable device must also be reliable for user friendly behavior.

The following are the Low Power Strategies that a designer must follow while designing any device.

Initially, the OS level which shows about the partitioning and power down. Next in Software level the Regularity, Locality and Concurrency (i.e., Compiler technology for low power, instruction scheduling) will be done. Next, the Architecture level part where Pipelining, Redundancy and Data Encoding (ISA, architectural design, memory hierarchy, HW extensions,
etc) are done, after that Circuit/logic level where the Logic styles, Transistor sizing and Energy recovery (Logic families, conditional clocking, adiabatic circuits, asynchronous design) will be done and finally in Technology level the Threshold reductions are done.

2.3 Main components of power consumption in digital VLSI circuits.

The main components of power consumption in digital VLSI circuits are Switching component; Short-circuit component, and Static power component. The Switching component is the power which is consumed while charging and discharging of the circuit capacitances during transistor switching. Short-circuit component occurs because of short-circuit current flowing from supply voltage to ground during transistor switching. And Static power component exists because of static and leakage currents in stable state of circuit cause this component of power consumption.

The average power dissipation for a CMOS circuit is the sum of dynamic power, static power and short circuit power as given in the Equation 3 and final form is given in Equation 4.

The average power dissipation for a CMOS circuit is given by:

$$P_{\text{avg}} = P_{\text{dynamic}} + P_{\text{static}} + P_{\text{short circuit}}$$

$$P_{\text{avg}} = V_{dd} \cdot f_{clk} \sum (V_{\text{Ising}} \cdot C_{\text{load}} \cdot \alpha i) + V_{dd} \sum I_{isc} + V_{dd}$$

The challenge that has been faced by VLSI designers is to find effective techniques and their efficient applications to get minimum power dissipation without any compromise on their performance evaluation parameters. Thus, the design of low power circuits with improved performance is a major concern of modern VLSI designs. The combination of certain logic styles and low power modules with low leakage circuit topologies may greatly reduce the limitations of deep-sub-micro-meter technologies. At the system level, in synchronous implementation of microprocessors, adder cells are the basic modules in a variety of arithmetic units such as arithmetic logical units, ripple carry adders, multipliers etc.

These days, as number of applications is increasing, the speed and portability are the major requirements of any smart device. The device size must be small, and it must have low-power high throughput circuitry. Sub circuits of any VLSI chip needs high speed of operation along with low-power consumption. Pass transistor circuits reduces the number of MOS transistors that are to be used in circuit, but it has drawback that the output voltage levels will no longer be same as the input voltage level. Each transistor in series has a lower voltage at its output than at its input.

From the Figure (1), the power consumption of the lead Intel microprocessors has been increasing significantly for almost every generation over the past 30 years. The frequency changes during this era from several MHz to 3 GHz. Figure (1) shows, at higher frequencies, the power dissipation is more.

Low power is required not only for portable applications but also for the reduction of power of high performance systems. Due to the requirement of large integration density and speed of
operation, systems with high clock frequencies are playing prominent role. These systems are using high speed processors and associated circuits which increase the power consumption. The cost associated with cooling, packaging and fans required by these systems to remove the heat generated because of power consumption is increasing significantly.

![Figure 1. Maximum power consumption of Intel Microprocessor](image)

**Figure 1. Maximum power consumption of Intel Microprocessor**

### 3. Previous Work on Adders

#### 3.1. CMOS Full Adder

Starting with basic CMOS full adder circuit, it consists of 28 transistors as shown in figure 2,[3] with less delay and high speed it also has good voltage swing, so the circuit’s performance will be good but its power dissipation is more because the transistor’s count is high so the area occupancy of the circuit is more. This CMOS logic is the basic logic operation of any circuit. It has PMOS in the pull up mode and NMOS in the pull down mode, so reducing the transistors count in the logic circuit is very difficult.
3.2. Single gate MOSFET Full Adder

In order to reduce the transistors count in full adder, a circuit is designed by using single gate MOSFET consists of 10 transistors as shown in figure (3). Here in this logic VDD supply voltage is not required as the outputs sum and carry will be produced from the three applied inputs [4]. The main drawback in it is that its voltage swing is poor. It requires high input voltages to obtain the outputs, because of which the power dissipation of the circuit will be more and also XNOR/XOR sub-circuit doesn’t provide stable output for applied zero inputs, because of which the logic of the circuit may differ for low transitions.

Figure 2. Basic CMOS full adder circuit using 28 transistors

Figure 3. Single gate MOSFET full adder circuit
3.3. Double gate MOSFET Full Adder

To overcome the drawbacks in Single gate MOSFET i.e., to increase the output voltage swing in Single gate MOSFET a double gate MOSFET is designed by connecting two single gate transistors back to back in such a way that sources and drains of two single gate MOSFET transistors are connected respectively as shown in figure (4). This circuit has 4 pairs of NMOS and 6 pairs of PMOS. The logic and analysis is similar to Single gate MOSFET except voltage swing. But the draw back in this case is that it consumes more power when compared to single gate MOSFET. Generally size of PMOS is doubled than size of NMOS but in Double gate MOSFET W/L ratio is maintained as 1:1 for all transistors, because of which there is leakage in PMOS transistors [4]. The W/L ratio is maintained so as to attain sufficient output voltage swing.

![Figure 4. Double gate MOSFET full adder circuit](image)

4. PROPOSED FULL ADDER CIRCUITS USING 22nm TECHNOLOGY

4.1. Transmission Gate full adder

A transmission gate has three inputs, called source, n-gate, and p-gate; and it has one output, called drain. The values at n-gate and p-gate are expected to be opposite to each other. If p-gate is 0 while n-gate is 1, then the value found at source is transmitted to drain. If p-gate is 1 while p-gate is 0, then the connection is broken, so the value at drain is left floating. In all other cases, drain receives an error output — unless source is floating, in which case drain is floating as well. as shown in figure (5). In this logic, one PMOS transistor and one NMOS transistor is connected back to back. This circuit has 4 pairs of Transmission Gates as shown in figure (5)[5]. The Transmission gates are used to increase the output voltage level of MOSFET’s which drives their output as input to a particular MOSFET for increase in output voltage swing. It overcomes the drawbacks in pass transistor logic and above mentioned logics in section II. As transistor count is reduced without effect in performance, this circuit is preferred. It can be operated at different loads and at different frequency of operations.
Table 1: Transmission gate full adder logic

<table>
<thead>
<tr>
<th>p-gate</th>
<th>n-gate</th>
<th>drain</th>
</tr>
</thead>
<tbody>
<tr>
<td>0</td>
<td>0</td>
<td>X*</td>
</tr>
<tr>
<td>0</td>
<td>1</td>
<td>source</td>
</tr>
<tr>
<td>1</td>
<td>0</td>
<td>Z</td>
</tr>
<tr>
<td>1</td>
<td>1</td>
<td>X*</td>
</tr>
<tr>
<td>X/Z</td>
<td>any</td>
<td>X*</td>
</tr>
<tr>
<td>Any</td>
<td>X/Z</td>
<td>X*</td>
</tr>
</tbody>
</table>

* If source is Z, drain is Z; otherwise drain is X.

4.2. GDI

The architecture of the 2:1 MUX using GDI method is shown in fig 6.[6] In this we have connected NMOS and PMOS gate along with a SEL line ‘A’, as in MUX. As we know that PMOS works on LOW and NMOS works on HIGH. So, when the SEL input is low, then the PMOS get activated, and show the input ‘B’ in the output and due to low input the NMOS idle, as it is activated in high input. For the same case, while the G input is high then the NMOS get activated, and show the input ‘C’ at the output. Thus this circuitry behaves as a 2-input MUX using ‘A’ as SEL line, and shows the favourable output as 2:1MUX. Now it's implemented the low power full adder circuit with the help of 2T MUX, done by GDI technique. It require total 6 numbers of 2T MUX having same characteristics to design a 12T full adder [7].

4.2.1. Gate Diffusion Input Technique:

GDI technique offers realization of extensive variety of logic functions using simple two transistor based circuit. This scheme gives for fast and low power circuit designs, which is reduce
the number of MOS transistors as compared to CMOS design and also other existing low power techniques, while the logic level swing and static power dissipation improves.

GDI technique based full adders have advantages over the full adder using pass transistor and is categorized by tremendous speed and low power. This technique has been described below:

1. The GDI cell consists of one nMOS and one pMOS. The structure looks CMOS inverter. Though in case of GDI both the sources and corresponding substrate terminals are not connected with supply and it can be randomly biased.

2. It has three input terminals: G (nMOS and pMOS gate input shorted), P (pMOS source input), and N (nMOS source input). The output is taken from D (nMOS and pMOS drain terminal shorted).

The digital circuit can be analyzed logically with the help of simple Boolean algebra. The output of each MUX can be analyzed to get sum & carry.

$$\text{MUX 1} = (BA^1 + CA)$$
$$\text{MUX 2} = (CA^1 + BA)$$
$$\text{MUX 3} = [(CA^1 + BA)C^1 + (BA^1 + CA)C]$$
$$\text{MUX 4} = A^1B + (A^1B + AC)B$$
$$\text{MUX 5} = (CA^1 + BA)B^1 + AB$$

4.2.2. Logic Analysis:

The digital circuit shown in figure (6), can be analyzed logically with the help of simple Boolean algebra [8]. The outputs of each MUX can be analyzed to get the sum and carry.
= AB'C' + A'BC' + ABC = SUM

5. SIMULATION RESULTS AND ANALYSIS

For the implementation of basic CMOS circuit the scaling parameters of 22nm technology is used, W/L ratio as 2:1 and Supply voltage of 0.9V is applied for better voltage swing as shown in figure (7). For single gate full adder the output logic cannot be obtained when \( V_{DD} = 0.9V \) as shown in figure (8). So that input voltage is raised up to 1.5V to obtain the output voltage which is shown in figure (9). Double gate MOSFET output logic is similar to the single gate MOSFET output logic and their output waveforms are shown in figure (10) and figure (11).
Figure 9. Single gate MOSFET simulation results in 22nm when $V_{DD}=1.5V$

Figure 10. Double gate MOSFET simulation result in 22nm when $V_{DD}=0.9V$

Figure 11. Double gate MOSFET simulation results in 22nm when $V_{DD}=1.5V$
The average power dissipation in different nano meter scales of full adder circuits is shown in table 1. From the table, in 90nm and 22nm technology the modified full adder consumes less power. Coming to 45nm single gate MOSFET consumes less power but as mentioned in section II, “it doesn’t give strong zero at carry at transition zero”, as shown in figure (12). So, the proposed full adder has less power dissipation with good performance compared to remaining circuits. Similarly, the power delay product analysis is done in table 2, the results shows that the proposed circuit had the best optimized results. In table 3, the results are taken by operating the full adder circuits with different frequencies and the minimum required supply voltages for operating with good voltage swings are tabulated. In figure (14) and figure (15) the power dissipation and power delay product of the circuits are shown respectively. Figure (13) shows the comparison of required voltage to run the circuit with good voltage swing with respect to frequency. Figure (16) shows the area comparison with different technologies. Figure (17) show the Layouts of GDI.
Table 2: Power dissipation in different scaling parameters

<table>
<thead>
<tr>
<th>S.No</th>
<th>FULL ADDER</th>
<th>90 nm</th>
<th>45 nm</th>
<th>22 nm</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>Basic CMOS</td>
<td>1.132</td>
<td>5.16</td>
<td>0.0362</td>
</tr>
<tr>
<td>2</td>
<td>Single gate MOSFET</td>
<td>0.1854</td>
<td>0.787</td>
<td>0.0362</td>
</tr>
<tr>
<td>3</td>
<td>Double gate MOSFET</td>
<td>1.1124</td>
<td>0.63</td>
<td>1.19</td>
</tr>
<tr>
<td>4</td>
<td>Transmission Gate</td>
<td>0.1549</td>
<td>0.408</td>
<td>0.0254</td>
</tr>
<tr>
<td>5</td>
<td>GDI</td>
<td>1.457</td>
<td>1.18</td>
<td>0.2846</td>
</tr>
</tbody>
</table>

Figure 14. Comparative analysis of Power Dissipation in different circuit modes

Table 3: Power delay product in different scaling parameters

<table>
<thead>
<tr>
<th>S.No</th>
<th>FULL ADDER</th>
<th>90nm</th>
<th>45nm</th>
<th>22nm</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>Basic CMOS</td>
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<td>3</td>
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<td>0.63</td>
<td>1.19</td>
</tr>
<tr>
<td>4</td>
<td>Transmission Gate</td>
<td>0.1549</td>
<td>0.408</td>
<td>0.02544</td>
</tr>
<tr>
<td>5</td>
<td>GDI</td>
<td>0.33</td>
<td>0.115</td>
<td>0.02393</td>
</tr>
</tbody>
</table>
Figure 15. Power delay product analysis

Table 1. Area in 22nm scaling technology with lambda=0.1um

<table>
<thead>
<tr>
<th>Model</th>
<th>CMOS</th>
<th>SGFA</th>
<th>DGFA</th>
<th>TGFA</th>
<th>GDIFA</th>
</tr>
</thead>
<tbody>
<tr>
<td>22nm</td>
<td>1740</td>
<td>726</td>
<td>1512</td>
<td>1173</td>
<td>858</td>
</tr>
<tr>
<td>XxY</td>
<td>87x20</td>
<td>33x22</td>
<td>63x24</td>
<td>51x23</td>
<td>39x22</td>
</tr>
</tbody>
</table>

Figure 16. Area Comparison of different models in 22nm technology
6. CONCLUSION

The performance parameters such as power, area and speed are evaluated for full adder using various nano-scale technologies. The simulation results shows that as we go on scaling there is drastic decrease in power consumption of full adder. It is not only achieves the low power but also operate at high speed. Post-Layout simulations shows the full design occupies the less area in 22nm technology compared to other nano scale technologies. The full adder designs are best suitable designs for the low power high-speed applications.

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